MODULAR BEAM DIAGNOSTICS INSTRUMENT DESIGN FOR CYCLOTRONS

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Beam Diagnostic requirements

+ Various beam diagnostic stations with different set of diagnostic components in all the beam regions (internal & external) of K-130 and K-500 Cyclotron).

Different types of control & monitoring hardware requirement for each type of component.

Requirement of unified hardware with unified control architecture with other subsystems.

Description of the second seco



EPICS IOC (Input/ Output controller) runs on Linux embedded Controller card and EPICS OPI (Operator

Interface) runs on PCs to handle communication and to control & monitor beam diagnostic components	
Modules are designed with basic functionalities like valve operation, probe/ slit/ viewer control, position read-out, Interlock, aperture control of beam line and communication	
Individual Serial port for each card for pseudo-parallel operation	
# Tools Used (Hardware & Firmware) #	Salient Features
	Customised instruments are easy to assemble according to requirement
ATMEL AVR family and C51 family controllers for functional cards	Modular design hence easy maintenance & upgradation, minimum downtime
IDEs (Instrument development Environment) like ATMEL Studio-6 and Keil-uVision 4 are used.	 EPIC introduction has removed PC dependency Liberty in developing functional cards using any tool
Serial port programmers and In-Circuit serial programmers are used for Flash programming	and by keeping the same command set Other EPICS oriented features
Control Architecture	
 A distributed control system (DCS), designed in a 3-layer architecture, monitors and controls all parameters The client-server data communications using channel access protocol of EPICS architecture Defined set of PVs (Process Variables) for each beam diagnostic component operation 	
The IOC (Input-Output controller) on controller card communicated with PCs to controls the diagnostic components and parameters and displayed using EPICS based (OPI) Operator Interface	
Present Status & Future Plans #	

• SCC inflector control and RTC X-Y Slit control are operational. Main-probe instrument is under development μC are being planned to be replaced by small FPGAs / CPLD (Complex programmable logic device)

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